

# Device Modeling Report

COMPONENTS: Silicon Carbide Schottky Diode  
PART NUMBER: CSD10060G  
MANUFACTURER: Cree, Inc.  
REMARK: Professional Model

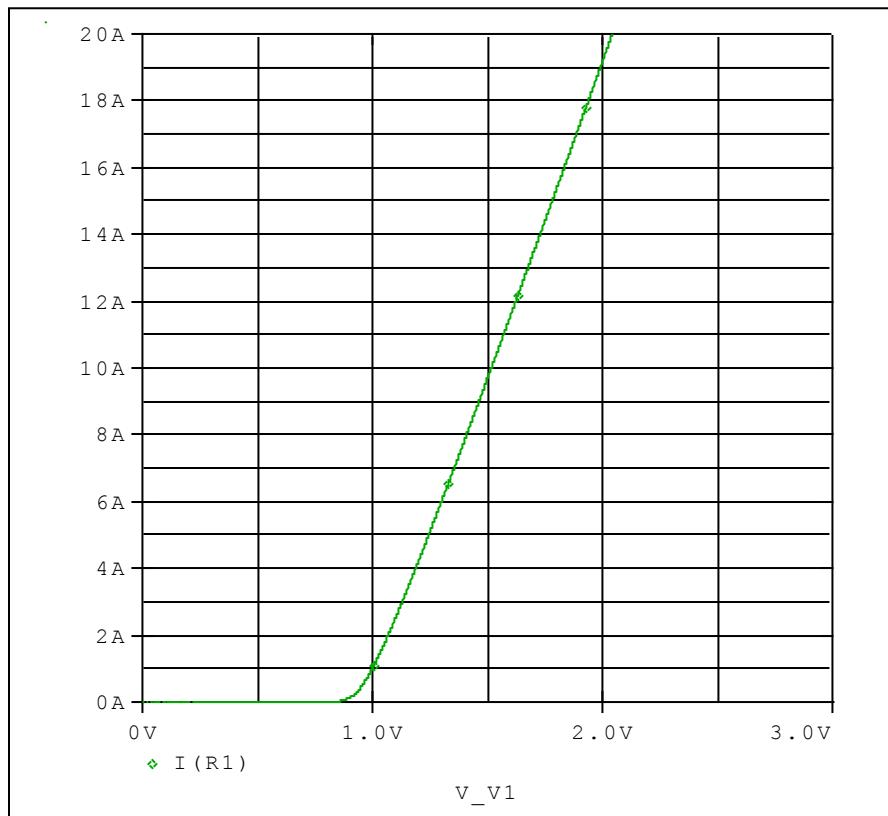


**Bee Technologies Inc.**

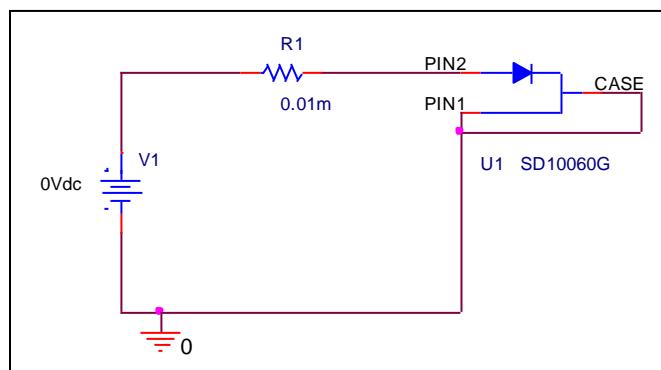
| PSpice model parameter | Model description                           |
|------------------------|---|
| IS                     | Saturation Current                          |
| N                      | Emission Coefficient                        |
| RS                     | Series Resistance                           |
| IKF                    | High-injection Knee Current                 |
| CJO                    | Zero-bias Junction Capacitance              |
| M                      | Junction Grading Coefficient                |
| VJ                     | Junction Potential                          |
| ISR                    | Recombination Current Saturation Value      |
| BV                     | Reverse Breakdown Voltage(a positive value) |
| IBV                    | Reverse Breakdown Current(a positive value) |
| TT                     | Transit Time                                |
| EG                     | Energy-band Gap                             |

## Forward Current Characteristic

Circuit Simulation Result

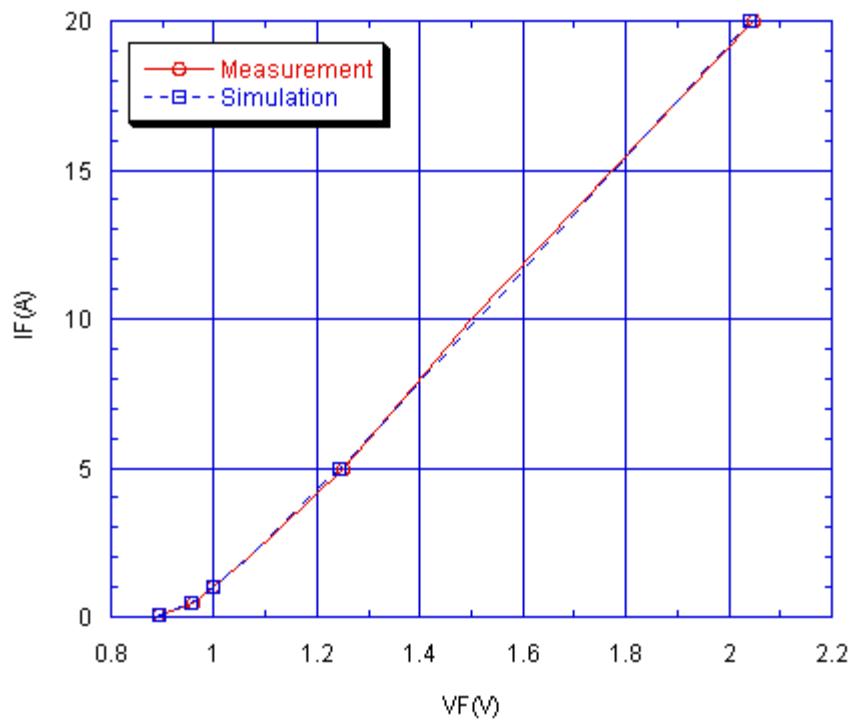


Evaluation Circuit



## Comparison Graph

Circuit Simulation Result

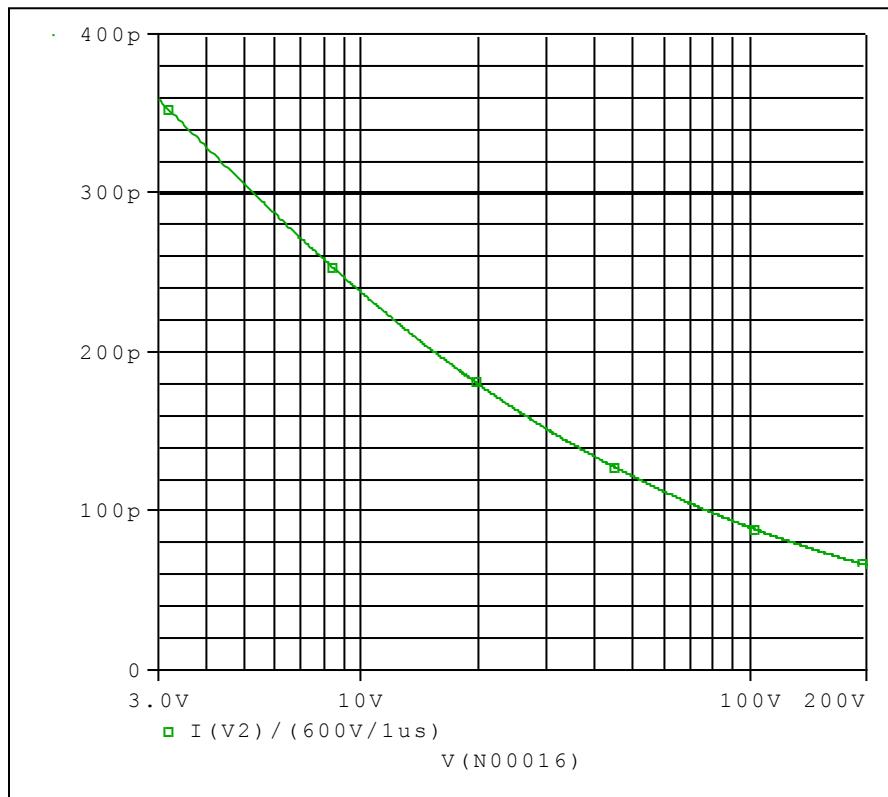


Simulation Result

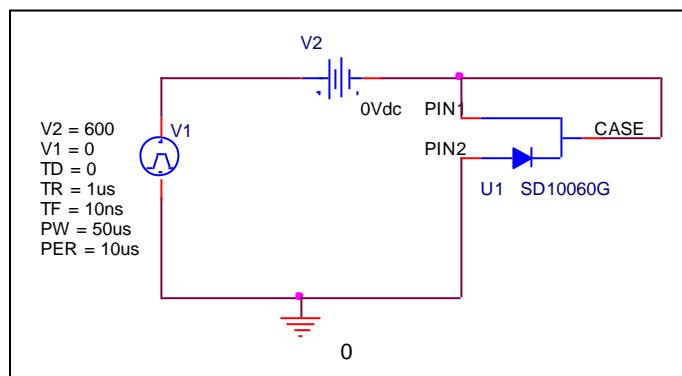
| $I_F(A)$ | $V_F(V)$    |            | Error(%) |
|----------|-------------|------------|----------|
|          | Measurement | Simulation |          |
| 0.1      | 0.895       | 0.894      | -0.112   |
| 0.2      | 0.915       | 0.916      | 0.109    |
| 0.5      | 0.960       | 0.957      | -0.313   |
| 1        | 1.000       | 0.989      | -1.112   |
| 2        | 1.070       | 1.065      | -0.469   |
| 5        | 1.250       | 1.245      | -0.402   |
| 10       | 1.500       | 1.510      | 0.662    |
| 20       | 2.050       | 2.040      | -0.490   |

## Junction Capacitance Characteristic

### Circuit Simulation Result

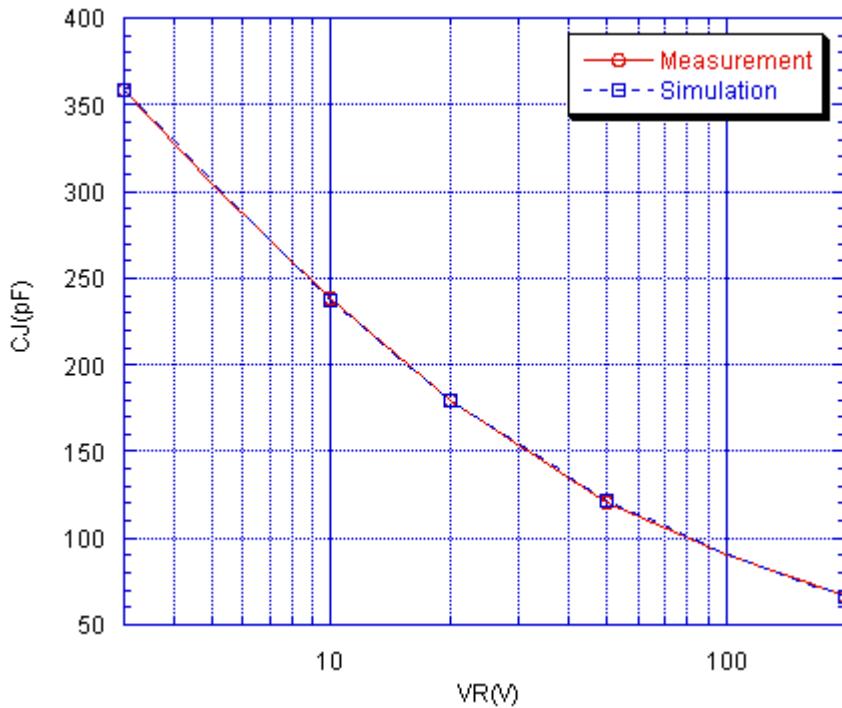


### Evaluation Circuit



## Comparison Graph

Circuit Simulation Result

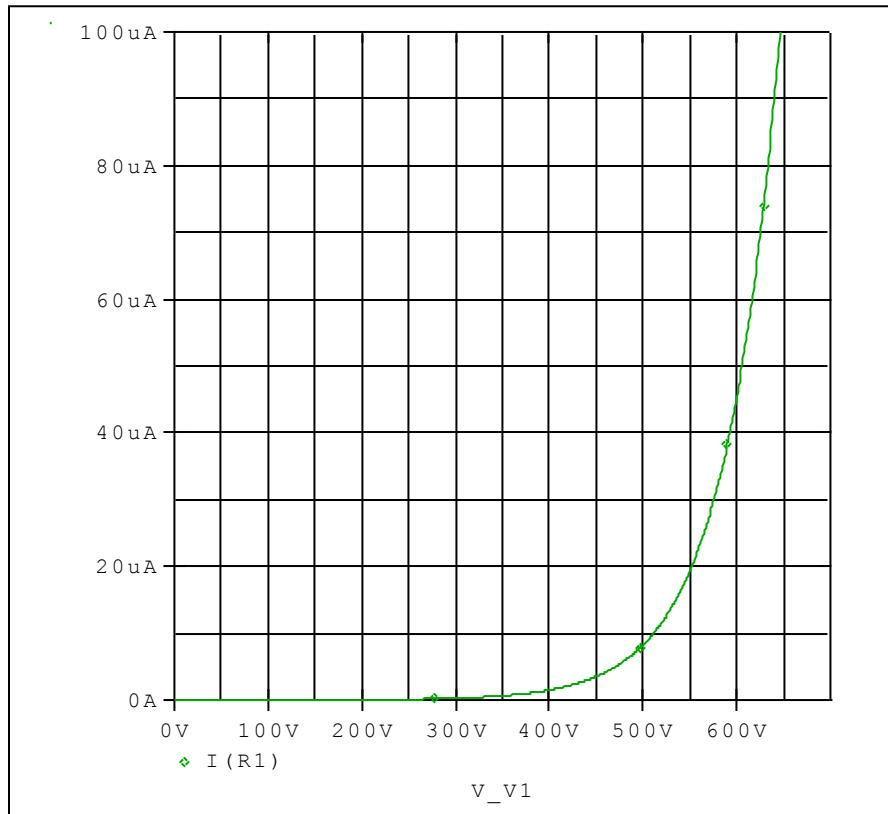


Simulation Result

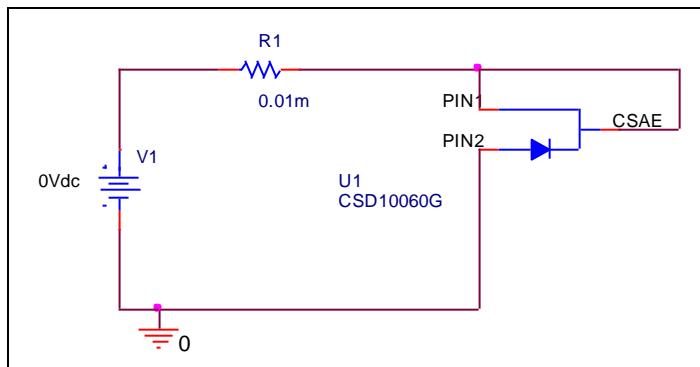
| $V_R$ (V) | Cj (pF)     |            | Error(%) |
|-----------|-------------|------------|----------|
|           | Measurement | Simulation |          |
| 5         | 304.000     | 305.500    | 0.491    |
| 10        | 238.000     | 237.500    | -0.211   |
| 20        | 180.000     | 179.900    | -0.056   |
| 50        | 121.000     | 121.500    | 0.412    |
| 100       | 90.000      | 90.000     | 0.000    |
| 200       | 66.000      | 66.200     | 0.302    |

## Reverse Characteristic

### Circuit Simulation Result

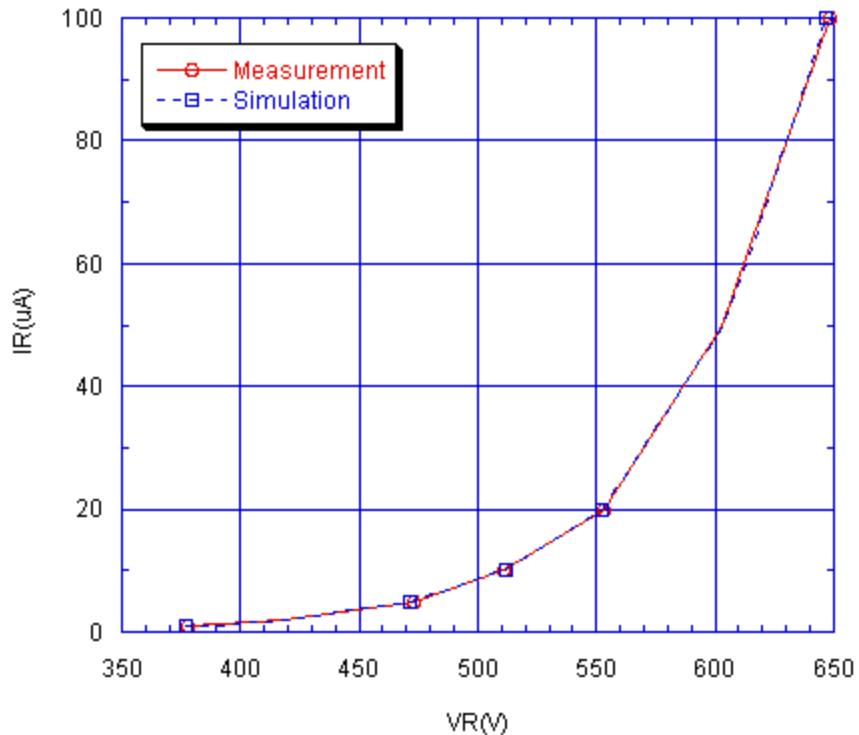


### Evaluation Circuit



## Comparison Graph

Circuit Simulation Result



Simulation Result

| $I_R$ (uA) | $V_R$ (V)   |            | Error(%) |
|------------|-------------|------------|----------|
|            | Measurement | Simulation |          |
| 1          | 378.000     | 376.700    | -0.345   |
| 2          | 418.000     | 417.200    | -0.192   |
| 5          | 473.000     | 471.000    | -0.425   |
| 10         | 511.000     | 511.500    | 0.098    |
| 20         | 553.000     | 552.000    | -0.181   |
| 50         | 607.000     | 606.000    | -0.165   |
| 100        | 648.000     | 647.000    | -0.155   |